

**Search Notes**

Application/Control No.

09/674,090

Examiner

Young J. Kim

Applicant(s)/Patent under  
Reexamination

EICHEN ET AL.

Art Unit

1637

**SEARCHED**

Class	Subclass	Date	Examiner
435	6	7/6/2005	YJK
	91.1	7/6/2005	YJK
	91.2	7/6/2005	YJK
536	24.3	7/6/2005	YJK
	24.33	7/6/2005	YJK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	7/6/2005	YJK
See enclosed for search strategy	7/6/2005	YJK
NPL: search terms: electrodes, conductive bridge, bridge, nanowire, device	7/6/2005	YJK